

Accelerating transient fault injection campaigns by using Dynamic HDL Slicing

Bagbaba, Ahmet Cagri; Jenihhin, Maksim; Raik, Jaan; Sauer, Christian 2019 IEEE Nordic Circuits and Systems Conference (NORCAS) : NORCHIP and International Symposium of System-on-Chip (SoC), 29-30 October 2019, Helsinki, Finland : proceedings in IEEE Xplore 2019 / 7 p. : ill <https://doi.org/10.1109/NORCHIP.2019.8906932>

Automated identification of application-dependent safe faults in automotive systems-on-a-chips

Bagbaba, Ahmet Cagri; Augusto da Silva, Felipe; Sonza Reorda, Matteo; Hamdioui, Said; **Jenihhin, Maksim;** Sauer, Christian Electronics 2022 / art. 319 <https://doi.org/10.3390/electronics11030319> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Combining fault analysis technologies for ISO26262 functional safety verification

Augusto da Silva, Felipe; **Bagbaba, Ahmet Cagri;** Hamdioui, Said; Sauer, Christian 2019 IEEE 28th Asian Test Symposium (ATS) : 10–13 December 2019, Kolkata, India : proceedings 2019 / p. 129–134 : ill <https://doi.org/10.1109/ATS47505.2019.00024>

Determined-safe faults identification : a step towards ISO26262 hardware compliant designs

Augusto da Silva, Felipe; **Bagbaba, Ahmet Cagri;** Sartoni, Sandro; Cantoro, Riccardo; Sonza Reorda, Matteo; Hamdioui, Said; Sauer, Christian 2020 25th IEEE European Test Symposium (ETS) 2020 / 6 p. : ill <https://doi.org/10.1109/ETS48528.2020.9131568>

Efficient fault injection based on dynamic HDL slicing technique

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Efficient methodology for ISO26262 functional safety verification

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Improving the confidence level in functional safety simulation tools for ISO 26262

Bagbaba, Ahmet Cagri; Augusto da Silva, Felipe; Sauer, Christian 2018 Design and Verification Conference (DVCON) Europe : [proceedings] 2018 / 6 p. : ill <https://dvcon-proceedings.org/document/improving-the-confidence-level-in-functional-safety-simulation-tools-for-iso-26262/> <https://zenodo.org/record/3361607#.Y0PHFnZByHs>

Representing gate-level SET faults by multiple SEU faults on RT-level

Bagbaba, Ahmet Cagri; Jenihhin, Maksim; Ubar, Raimund-Johannes; Sauer, Christian 2020 IEEE 26th International Symposium on On-Line Testing and Robust System Design (IOLTS), 13-15 July 2020 : proceedings 2020 / art. 19889351, 6 p. : ill <https://doi.org/10.1109/IOLTS50870.2020.9159715>

Use of formal methods for verification and optimization of fault lists in the scope of ISO26262

Augusto da Silva, Felipe; **Bagbaba, Ahmet Cagri;** Hamdioui, Said; Sauer, Christian 2018 Design and Verification Conference (DVCON) Europe : [proceedings] 2018 / 6 p. : ill <https://repository.tudelft.nl/islandora/object/uuid%3Adbd7f22d-0324-45f5-9180-8fe3fc95a9ce>